

SEMiX151GAL12E4s



Trench IGBT Modules

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Features

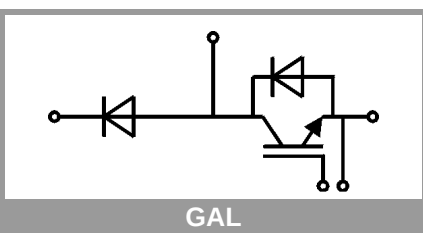
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$ with positive temperature coefficient
- High short circuit capability
- UL recognized, file no. E63532

Typical Applications*

- AC inverter drives
- UPS
- Electronic Welding

Remarks

- Case temperature limited to $T_C=125^{\circ}\text{C}$ max.
- Product reliability results are valid for $T_J=150^{\circ}\text{C}$



Absolute Maximum Ratings				
Symbol	Conditions		Values	Unit
IGBT				
V _{CES}			1200	V
I _C	T _j = 175 °C	T _c = 25 °C	232	A
		T _c = 80 °C	179	A
I _{Cnom}			150	A
I _{CRM}	I _{CRM} = 3xI _{Cnom}		450	A
V _{GES}			-20 ... 20	V
t _{psc}	V _{CC} = 800 V V _{GE} ≤ 20 V V _{CES} ≤ 1200 V	T _j = 150 °C	10	μs
T _j			-40 ... 175	°C
Inverse diode				
I _F	T _j = 175 °C	T _c = 25 °C	189	A
		T _c = 80 °C	141	A
I _{Fnom}			150	A
I _{FRM}	I _{FRM} = 3xI _{Fnom}		450	A
I _{FSM}	t _p = 10 ms, sin 180°, T _j = 25 °C		900	A
T _j			-40 ... 175	°C
Freewheeling diode				
I _F	T _j = 175 °C	T _c = 25 °C	189	A
		T _c = 80 °C	141	A
I _{Fnom}			150	A
I _{FRM}	I _{FRM} = 3xI _{Fnom}		450	A
I _{FSM}	t _p = 10 ms, sin 180°, T _j = 25 °C		900	A
T _j			-40 ... 175	°C
Module				
I _{t(RMS)}			600	A
T _{stg}			-40 ... 125	°C
V _{isol}	AC sinus 50Hz, t = 1 min		4000	V

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
IGBT						
V _{CE(sat)}	I _C = 150 A	T _j = 25 °C		1.8	2.05	V
	V _{GE} = 15 V chipelevel	T _j = 150 °C		2.2	2.4	V
V _{CE0}		T _j = 25 °C		0.8	0.9	V
		T _j = 150 °C		0.7	0.8	V
r _{CE}		T _j = 25 °C		6.7	7.7	mΩ
	V _{GE} = 15 V	T _j = 150 °C		10.0	10.7	mΩ
V _{GE(th)}	V _{GE} =V _{CE} , I _C = 6 mA		5	5.8	6.5	V
I _{CES}	V _{GE} = 0 V	T _j = 25 °C		0.1	0.3	mA
	V _{CE} = 1200 V	T _j = 150 °C				mA
C _{ies}		f = 1 MHz		9.3		nF
C _{oes}	V _{CE} = 25 V	f = 1 MHz		0.58		nF
C _{res}	V _{GE} = 0 V	f = 1 MHz		0.51		nF
Q _G	V _{GE} = - 8 V...+ 15 V			850		nC
R _{Gint}	T _j = 25 °C			5.00		Ω



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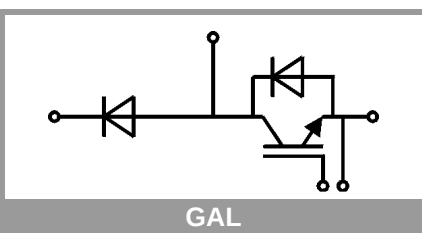
Typical Applications*

- AC inverter drives
- UPS
- Electronic Welding

Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_J=150^\circ\text{C}$

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
t _{d(on)}	V _{CC} = 600 V	T _j = 150 °C		204		ns
t _r	I _C = 150 A	T _j = 150 °C		42		ns
E _{on}	R _{G on} = 1 Ω	T _j = 150 °C		16.6		mJ
t _{d(off)}	R _{G off} = 1 Ω	T _j = 150 °C		468		ns
t _f	di/dt _{on} = 3900 A/μs	T _j = 150 °C		91		ns
E _{off}	di/dt _{off} = 2000 A/μs	T _j = 150 °C		18.4		mJ
R _{th(j-c)}	per IGBT				0.19	K/W
Inverse diode						
V _F = V _{EC}	I _F = 150 A	T _j = 25 °C		2.1	2.46	V
	V _{GE} = 0 V chip	T _j = 150 °C		2.1	2.4	V
V _{F0}		T _j = 25 °C	1.1	1.3	1.5	V
		T _j = 150 °C	0.7	0.9	1.1	V
r _F		T _j = 25 °C	4.3	5.6	6.4	mΩ
		T _j = 150 °C	6.7	7.8	8.5	mΩ
I _{RRM}	I _F = 150 A	T _j = 150 °C		115		A
Q _{rr}	di/dt _{off} = 3400 A/μs	T _j = 150 °C		23		μC
E _{rr}	V _{GE} = -15 V V _{CC} = 600 V	T _j = 150 °C		8.9		mJ
R _{th(j-c)}	per diode				0.31	K/W
Freewheeling diode						
V _F = V _{EC}	I _F = 150 A	T _j = 25 °C		2.1	2.5	V
	V _{GE} = 0 V chip	T _j = 150 °C		2.1	2.4	V
V _{F0}		T _j = 25 °C	1.1	1.3	1.5	V
		T _j = 150 °C	0.7	0.9	1.1	V
r _F		T _j = 25 °C	4.3	5.6	6.4	mΩ
		T _j = 150 °C	6.7	7.8	8.5	mΩ
I _{RRM}	I _F = 150 A	T _j = 150 °C		115		A
Q _{rr}	di/dt _{off} = 3400 A/μs	T _j = 150 °C		23		μC
E _{rr}	V _{GE} = -15 V V _{CC} = 600 V	T _j = 150 °C		8.9		mJ
R _{th(j-c)}	per diode				0.31	K/W
Module						
L _{CE}				16		nH
R _{CC'+EE'}	res., terminal-chip	T _C = 25 °C		0.7		mΩ
		T _C = 125 °C		1		mΩ
R _{th(c-s)}	per module			0.075		K/W
M _s	to heat sink (M5)		3		5	Nm
M _t		to terminals (M6)	2.5		5	Nm
						Nm
w					145	g
Temperatur Sensor						
R ₁₀₀	T _C =100°C (R ₂₅ =5 kΩ)			493 ± 5%		Ω
B _{100/125}	R _(T) =R ₁₀₀ exp[B _{100/125} (1/T-1/T ₁₀₀)]; T[K];			3550 ±2%		K



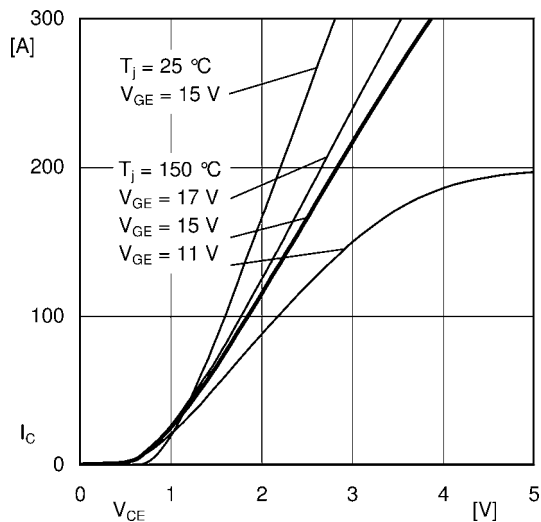


Fig. 1: Typ. output characteristic, inclusive $R_{CC'} + E_E$

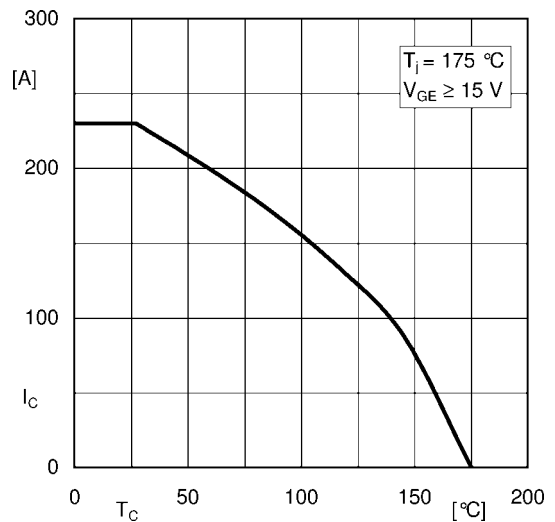


Fig. 2: Rated current vs. temperature $I_C = f(T_C)$

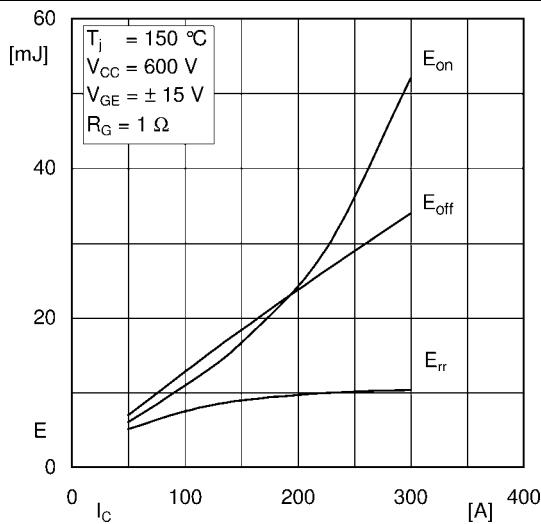


Fig. 3: Typ. turn-on /-off energy = $f(I_C)$

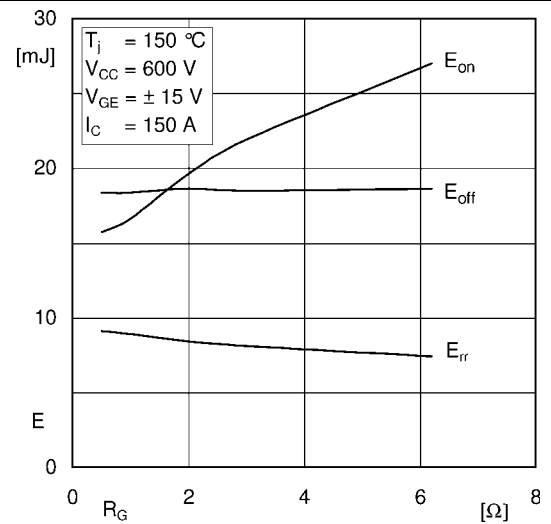


Fig. 4: Typ. turn-on /-off energy = $f(R_G)$

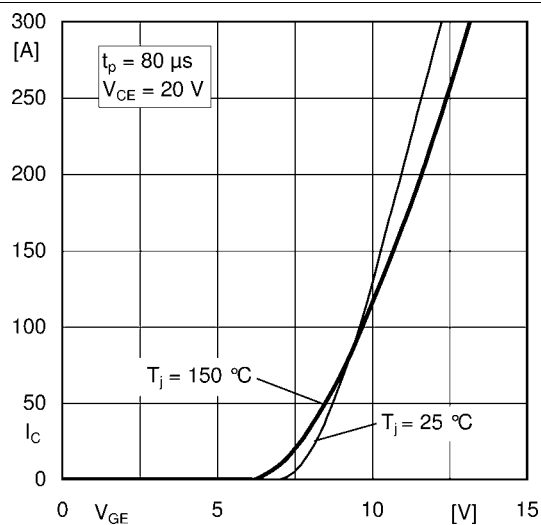


Fig. 5: Typ. transfer characteristic

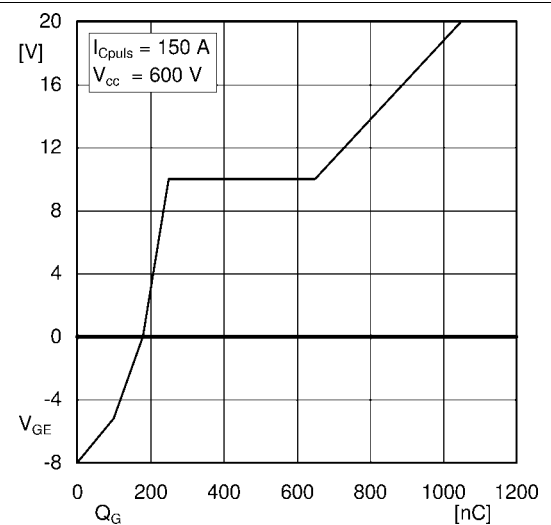


Fig. 6: Typ. gate charge characteristic

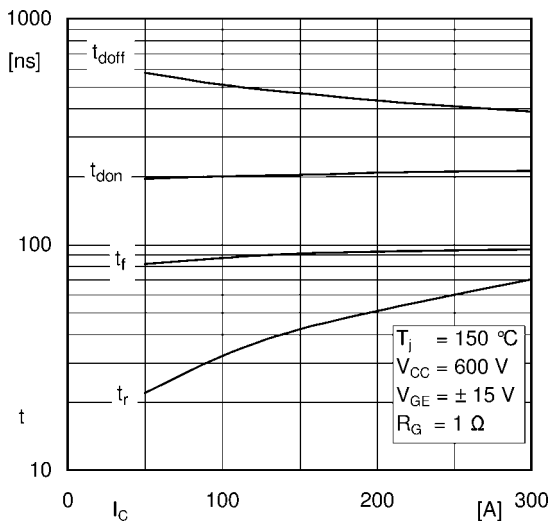


Fig. 7: Typ. switching times vs. I_C

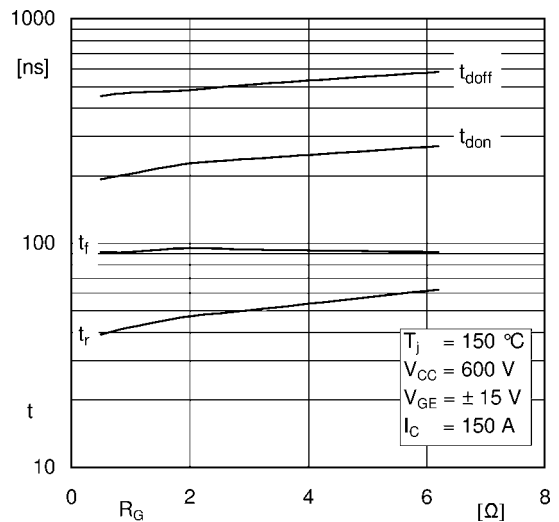


Fig. 8: Typ. switching times vs. gate resistor R_G

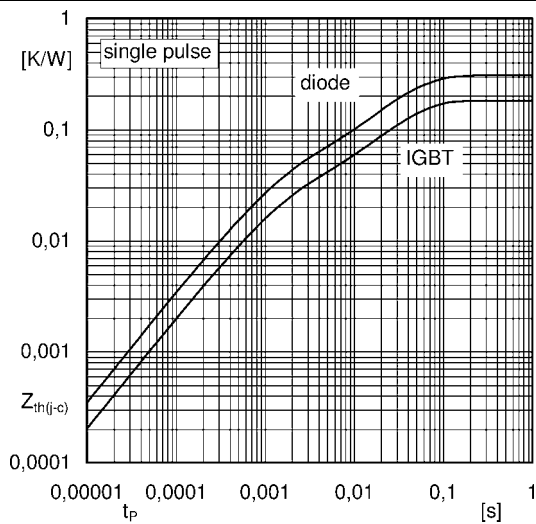


Fig. 9: Typ. transient thermal impedance

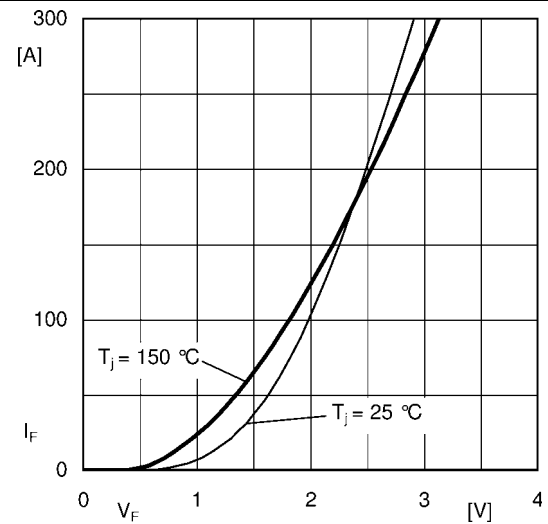


Fig. 10: Typ. CAL diode forward charact., incl. $R_{CC'+EE'}$

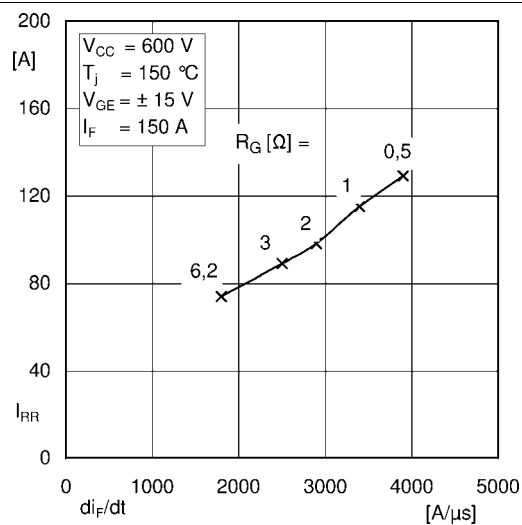


Fig. 11: Typ. CAL diode peak reverse recovery current

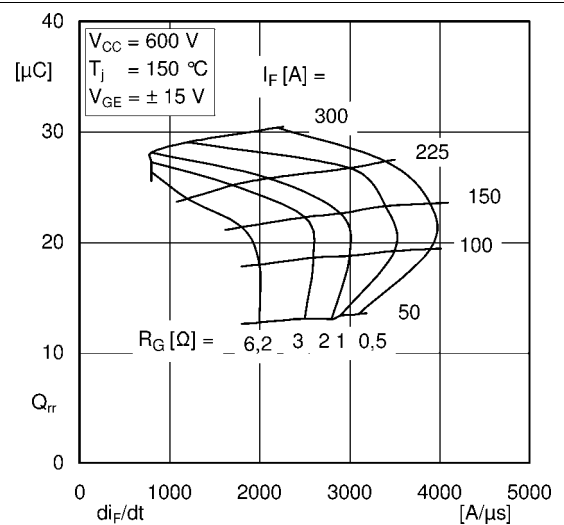
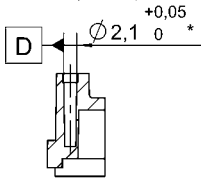


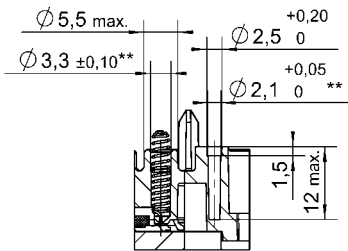
Fig. 12: Typ. CAL diode recovery charge



screw duct
(left top) :
F-F (1 : 1)

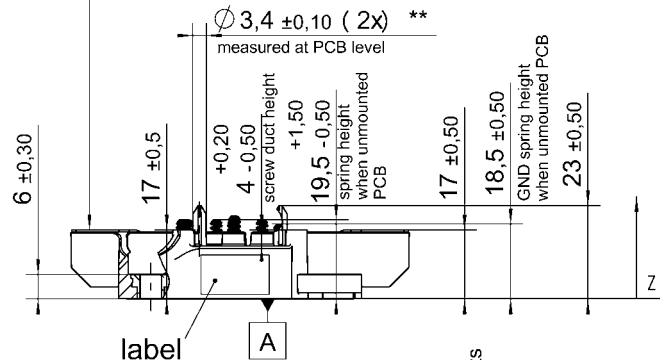


screw duct (4x)
spring duct (8x) :
G-G (1:1)

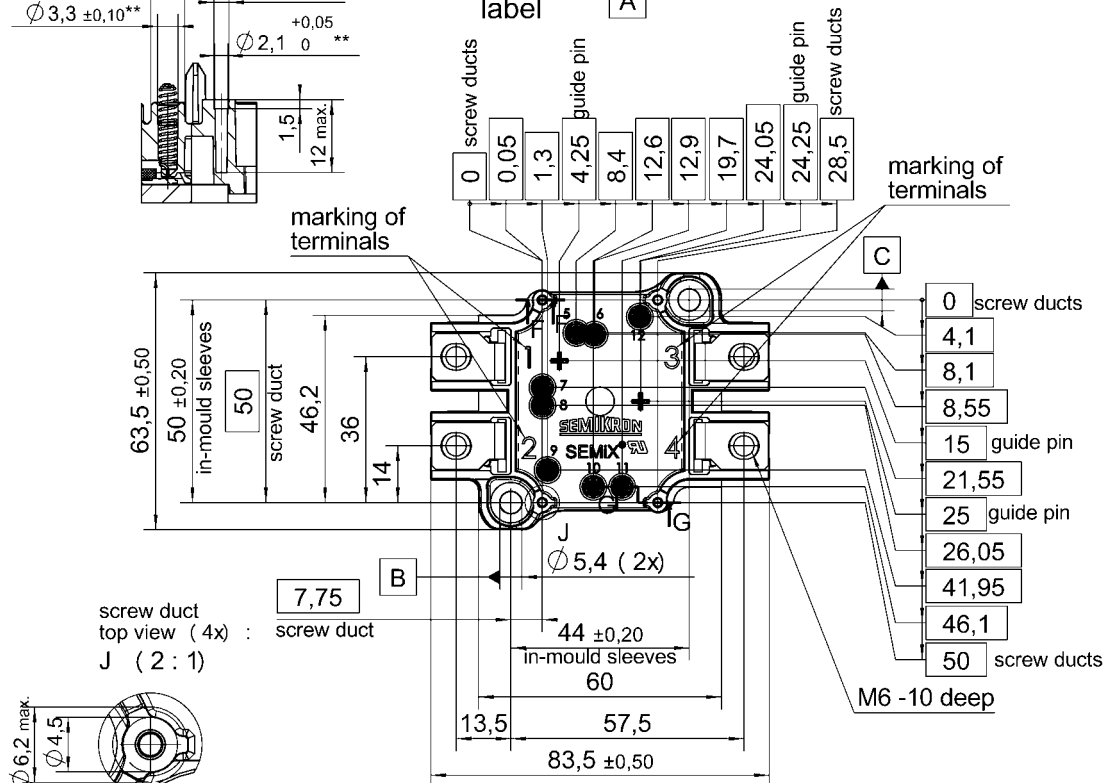


	0,3	connector 1-2 / 3-4
	0,2	each connector A

general tolerance:
ISO 2768-mK
ISO 8015



All measures in Z-direction
valid when mounted to heat sink



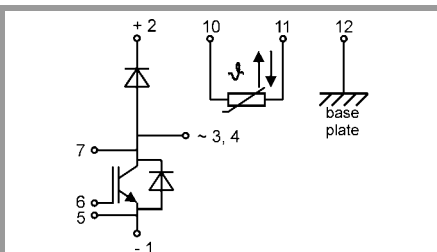
*screw duct left / top with
**screw ducts / guide pins / spring ducts with

	$\varnothing$ 0,2	A	B	C
	$\varnothing$ 0.2	A	D	C

Rules for the contact PCB:

- holes guidepins = $\varnothing 4 \pm 0,1$ / position tolerance $\pm 0,1$
- holes for screws = $\varnothing 2,9 \pm 0,1$ / position tolerance $\pm 0,1$
- spring contact pad = $\varnothing 3,6 \pm 0,1$ / position tolerance $\pm 0,1$

SEMIX 1s



spring configuration

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX

* The specifications of our components may not be considered as an assurance of component characteristics. Components have to be tested for the respective application. Adjustments may be necessary. The use of SEMIKRON products in life support appliances and systems is subject to prior specification and written approval by SEMIKRON. We therefore strongly recommend prior consultation of our personal.